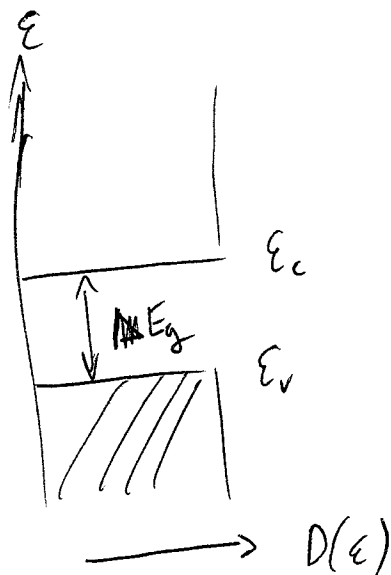


(1)

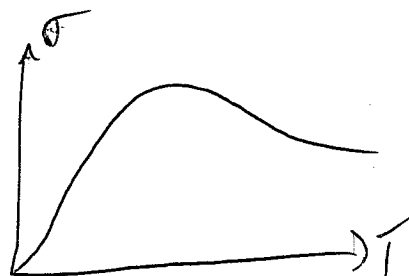
Semiconductors



- Just insulators with (relatively) small band gaps $E_g \lesssim 1 \text{ eV}$

- Why distinguish semiconductors & insulators?

(1) Noticeable conduction at finite T



$$\sigma(T) \sim e^{-E_g/2k_B T}$$

at low T

$$\sigma = \frac{ne^2\tau}{m}$$

low T increase comes from τ 's.

(2) Semiconductors are technologically very useful

Why?

- (1) Easily manipulated by "doping" w/ impurities. (Substantially decreases carrier τ imp. for τ 's)

- (2) " " by applied $\vec{E}$ -fields.

(2)

Examples: Si, Ge

Band structure: usually describe using effective mass approx.

$$E(\vec{k}) = E_c + \frac{\hbar^2}{2} k_i M_{ij}^{-1} k_j \quad (\text{conduction band})$$

$$E(\vec{k}) = E_v - \frac{\hbar^2}{2} k_i M_{ij}^{-1} k_j \quad (\text{valence "})$$

• (can diagonalize M^{-1} , M)

→ Measure M^{-1} by cyclotron resonance

$$(\text{recall } T = \frac{2\pi m^* c}{eB}, \quad m^* = \left(\frac{\det M}{M_{zz}} \right)^{1/2})$$

• Apply microwave field in resonance w/ periodic motion of orbits.



of carriers (clean case).

(3)

$$n_c(T) = p_v(T)$$

↑
el's in
cond. band.

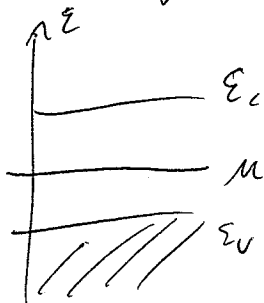
↑
holes
in val. band

$$n_c(T) = \int_{\epsilon_c}^{\infty} d\epsilon g_c(\epsilon) \frac{1}{e^{(\epsilon-\mu)/k_B T} + 1}$$

$$p_v(T) = \int_{-\infty}^{\epsilon_v} d\epsilon g_v(\epsilon) \left(1 - \frac{1}{e^{(\epsilon-\mu)/k_B T} + 1} \right)$$

$$= \int_{-\infty}^{\epsilon_v} d\epsilon g_v(\epsilon) \frac{1}{e^{(\mu-\epsilon)/k_B T} + 1}$$

Assume: $k_B T \ll E_g$ and μ lies near middle of gap:



• Will check consistent.

$$\Rightarrow \epsilon_c - \mu \gg k_B T$$

$$\mu - \epsilon_v \gg k_B T$$

$$\Rightarrow n_c(T) \approx \left[\int_{\epsilon_c}^{\infty} d\epsilon g_c(\epsilon) e^{-(\epsilon-\epsilon_c)/k_B T} \right] e^{-(\epsilon_c-\mu)/k_B T} = N_c(T) e^{-(\epsilon_c-\mu)/k_B T}$$

$$p_v(T) \approx \left[\int_{-\infty}^{\epsilon_v} d\epsilon g_v(\epsilon) e^{-(\epsilon_v-\epsilon)/k_B T} \right] e^{-(\mu-\epsilon_v)/k_B T} = P_v(T) e^{-(\mu-\epsilon_v)/k_B T}$$

Using result from last MW:

(4)

$$g_{c,v}(\epsilon) = \sqrt{2|\epsilon - \epsilon_{c,v}|} \frac{m_{c,v}^{*3/2}}{\hbar^3 \pi^2} ; \quad m_{c,v}^* = (\det M_{c,v})^{1/3}$$

$$\Rightarrow N_{c,v}(T) = \frac{1}{4} \left(\frac{2m_{c,v}^* k_B T}{\pi \hbar^2} \right)^{3/2}$$

Pa

sim. for $P_v(T)$

Note: $n_c p_v = N_c P_v e^{-E_g/k_B T} \rightarrow$ No μ -dependence

• So, for haven't used $N_c = p_v$, which gives

$$\cancel{\left(\frac{m_c^*}{\hbar^3}\right)} (m_c^*)^{3/2} e^{-(\epsilon_c - \mu)/k_B T} = (m_v^*)^{3/2} e^{-(\mu - \epsilon_v)/k_B T}$$

$$\Rightarrow \mu = \underbrace{\frac{\epsilon_c + \epsilon_v}{2}}_{\text{middle of gap}} + \underbrace{\frac{3}{4} k_B T \ln \left(\frac{m_v^*}{m_c^*} \right)}_{\text{small}}$$

"Extrinsic" case (w/ impurities)

(5)

- ~~• Will see that now $N_c \neq p_v$; $N_c = p_v \pm \Delta n$~~
- Main effect is to introduce extra carriers.

e.g. Si doped with P

$$\text{Si} = [\text{Ne}] 3s^2 3p^2$$

$$\text{P} = [\text{Ne}] 3s^2 3p^3 \rightarrow 1 \text{ extra electron} \\ \text{ \& } 1 \text{ extra + charge}$$

$\Rightarrow$ Single P impurity introduces localized + charge @ nucleus
& extra - charged electron.

$\rightarrow$ Electron binds to P impurity from potential

$$V(r) = - \frac{e^2}{\epsilon r}$$

ϵ dielectric const.

Also, kinetic energy $\frac{\hbar^2}{2m} \nabla^2 \rightarrow \frac{\hbar^2}{2m^*} \nabla^2$
(simplest case)

(6)

$\Rightarrow$ Binding energy $E_d = E_c - \frac{m^* e^4}{\epsilon^2 2 \hbar^2} = E_c - \frac{m^*}{m} \frac{1}{\epsilon^2} \times 13.6 \text{ eV}$

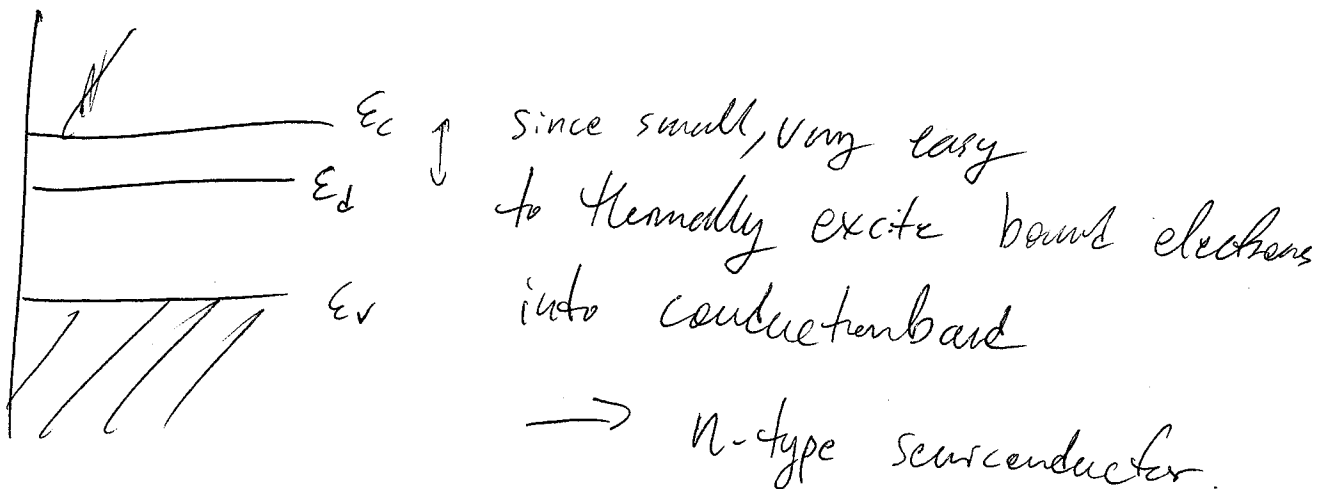
$\uparrow$
 $d \rightarrow$ "donor impurity"

Size of bound state: $r_0 = \frac{\hbar^2 \epsilon}{m^* e^2} = \frac{m}{m^*} \epsilon a_0$

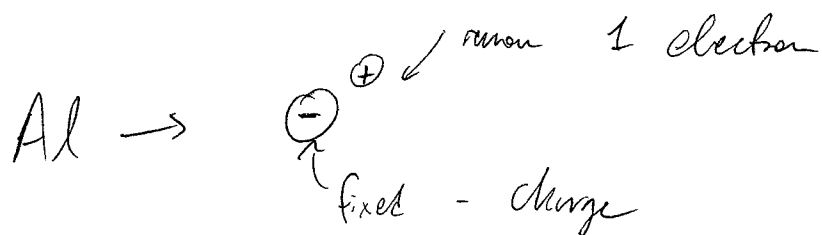
Typically, $m^* < m$ and $\epsilon \gtrsim 10$

$\Rightarrow r_0$ is large compared to lattice spacing

& $E_c - E_d$ small compared to E_g .



Acceptors e.g. Al in Si:



Think of in 2 steps:

(1) Add fixed - charge

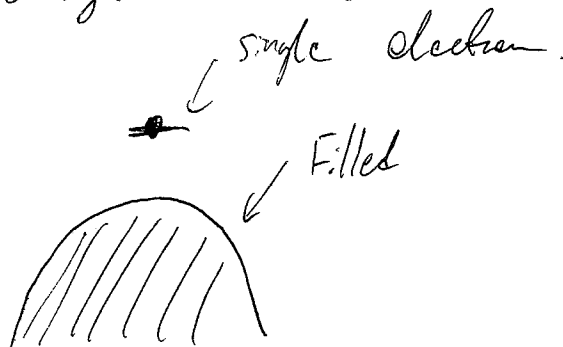
(2) Remove electron.

(1) $H = + \frac{\hbar^2}{2m^*} \nabla^2 + \frac{e^2}{\epsilon r} \rightarrow$



↓
Assume only top of
valence band
states important

(2) ~~For overall charge neutrality:~~



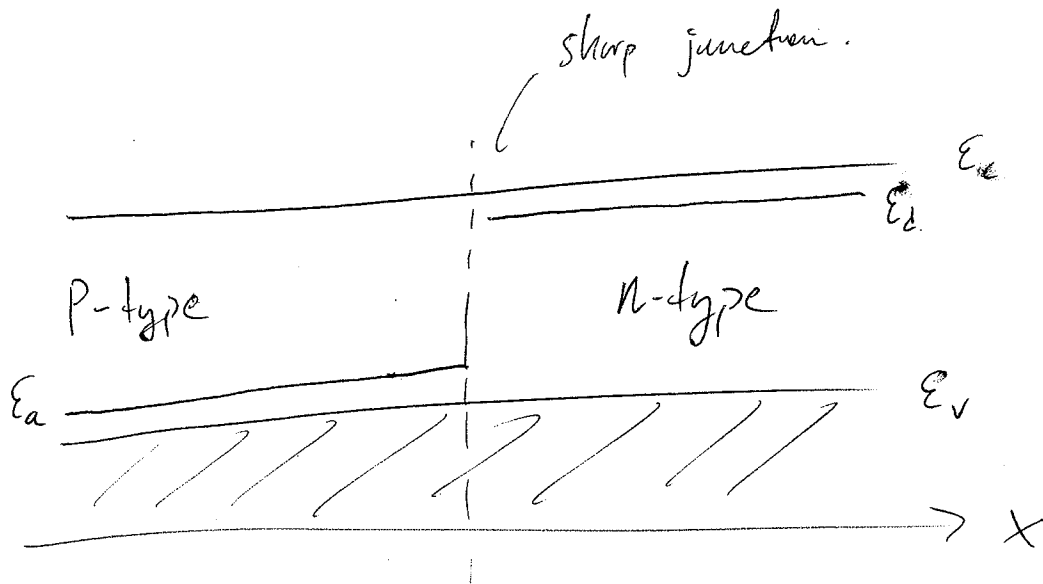
Argument:

All these states come from valence band $\rightarrow$ so same # of states as in v.b. So, before step 2, the bud state is filled.

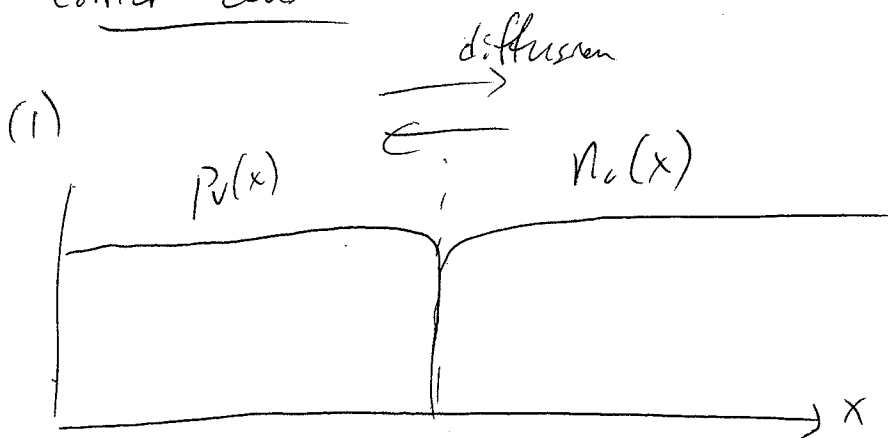
8

P-N junction (diode)

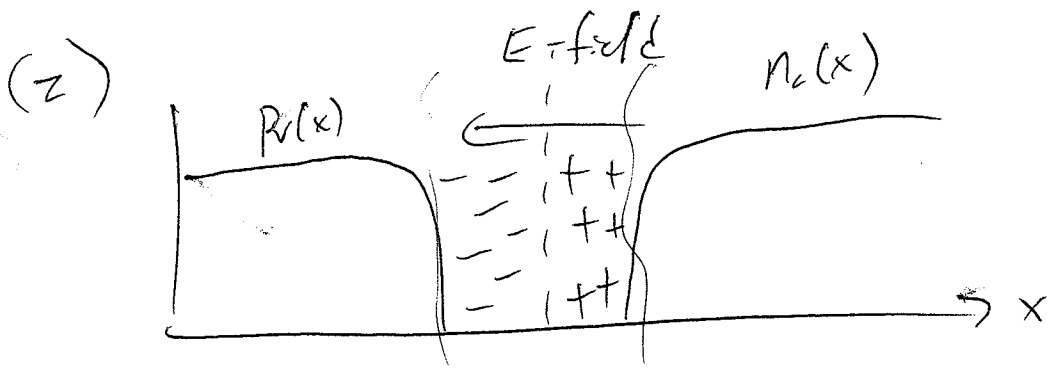
• First equilibrium.



• Carrier densities :

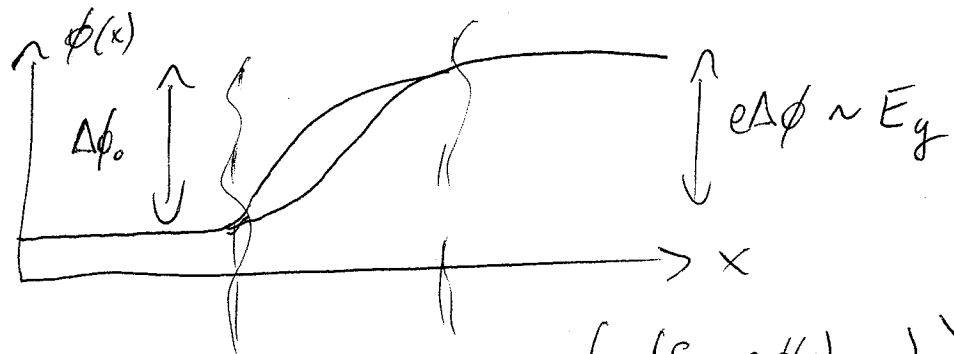


(9)



• E field opposes diffusion $\rightarrow$ ~~it~~ it reaches equilibrium.

Let $\phi(x)$ be electrostatic potential



Shock Model :
$$n_c(x) = N_c(T) \exp\left(\frac{-(E_c - e\phi(x) - \mu)}{k_B T}\right)$$

= (slowly varying potential)

Now,
$$P_v(x) \stackrel{=}{=} P_v(\infty) \exp\left[\frac{-(e\phi(x) - e\phi(\infty))}{k_B T}\right]$$

$\Rightarrow P_v(x) \approx 0$ in depletion layer.

Apply voltage

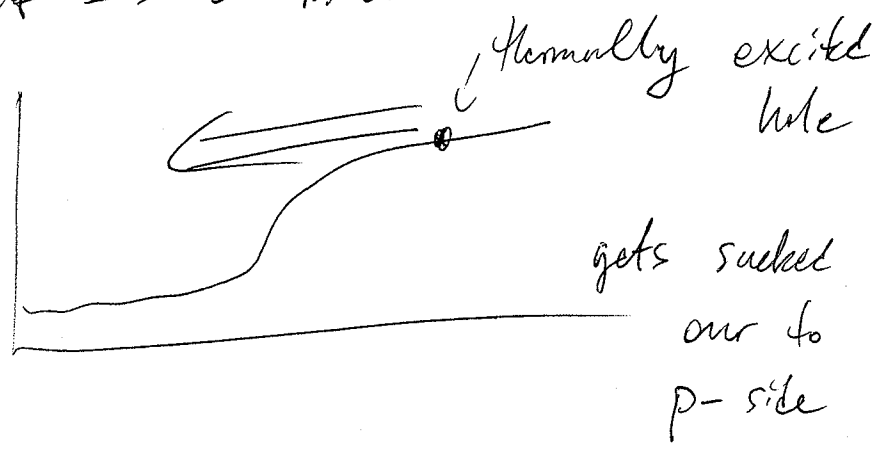
$V > 0$ means higher $\phi(x)$ on p-type side

$$\Delta\phi = \Delta\phi_0 - V$$

$\rightarrow V > 0$ tends to shrink depletion layer
 $V < 0$ enlarges it.

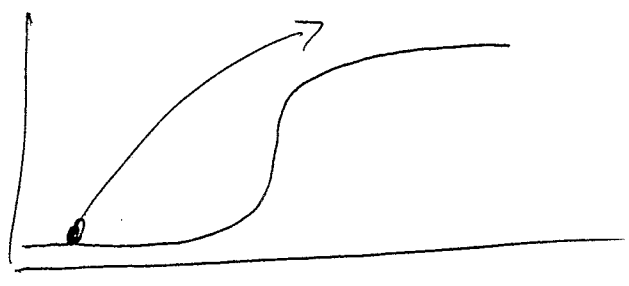
Consider hole current $\rightarrow$ 2 kinds:

(1) J_h^{gen}



- Not sensitive to V , since many hole on the n-side gets sucked over

(2) J_h^{rec}



- Hole jumps over barrier from p $\rightarrow$ n.
- Sensitive to V

• Expect $J_n^{\text{rec}} \propto e^{eV/k_B T}$

$$J_n = J_n^{\text{rec}} - J_n^{\text{gen}} \quad \text{and} \quad J_n^{\text{gen}} \propto \text{const.} \quad (\text{no } V\text{-dep.})$$

$$J_n(V=0) = 0.$$

~~4/8~~

$$\Rightarrow J_n = J_n^{\text{gen}} (e^{eV/k_B T} - 1)$$

• Same analysis works for electrons.

